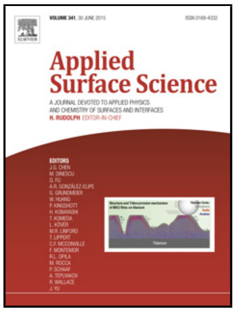

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PII: S0169-4332(16)30342-7
DOI: http://dx.doi.org/doi:10.1016/j.apsusc.2016.02.164
Reference: APSUSC 32682

To appear in: *APSUSC*

Received date: 10-11-2015
Revised date: 18-2-2016
Accepted date: 18-2-2016

Please cite this article as: Baojun Yan, Shulin Liu, Yuzhen Yang, Yuekun Heng, Band alignment of atomic layer deposited MgO/Zn0.8Al0.2O heterointerface determined by charge corrected X-ray photoelectron spectroscopy, Applied Surface Science http://dx.doi.org/10.1016/j.apsusc.2016.02.164

Band alignment of atomic layer deposited MgO/$Zn_{0.8}Al_{0.2}O$ heterointerface determined by charge corrected X-ray photoelectron spectroscopy

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